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Application/Control No.	Applicant(s)/Patent under Reexamination
10/691,440	ATKEY ET AL.
Examiner	Art Unit
Trinh T. Nguyen	3644

	SEARCHED			
Class	Subclass	Date	Examiner	
updated	all	8/15/2005	TTN	
previou 5	searches	\	I	
as	indicated			
on	search			
notes	2/3/05			

INT	INTERFERENCE SEARCHED		
Class	Subclass	Date	Examiner

SEARCH NOTES (INCLUDING SEARCH STRATEGY)			
	DATE	EXMR	
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